

August 2001

FDP2570/FDB2570

150V N-Channel PowerTrench® MOSFET

General Description

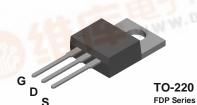
This N-Channel MOSFET has been designed specifically for switching on the primary side in the isolated DC/DC converter application. Any application requiring a 150V MOSFETs with low on-resistance and fast switching will benefit.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable RDS_(ON) specifications.

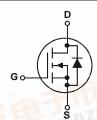
The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 22 A, 150 V. $R_{DS(ON)} = 80 \text{ m}\Omega \ @ \ V_{GS} = 10 \text{ V}$ $R_{DS(ON)} = 90 \text{ m}\Omega \ @ \ V_{GS} = 6 \text{ V}$
- Low gate charge (40nC typical)
- · Fast switching speed
- High performance trench technology for extremely low R_{DS(ON)}
- 175°C maximum junction temperature rating







S TO-263AB FDB Series

Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		150	V
V _{GSS}	Gate-Source Voltage		± 20	V
I _D	Drain Current - Continuous	(Note 1)	22	А
	- Pulsed	(Note 1)	50	Α
P _D	Total Power Dissipation @ T _C = 25°C		93	W
	Derate above 25°C		0.63	W°/C
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-65 to +175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction-to-Case	1.6	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	62.5	°C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
FDB2570	FDB2570	13"	24mm	800 units
FDP2570	FDP2570	Tube	n/a	45 units



Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Drain-Sc	ource Avalanche Ratings (Note	1)		ı		
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	$V_{DD} = 75 \text{ V}, \qquad I_{D} = 11 \text{ A}$			375	mJ
I _{AR}	Maximum Drain-Source Avalanche Current				11	Α
Off Char	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	150			V
ΔBV _{DSS} ΔT _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		154		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 120 V, V _{GS} = 0 V			1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$			-100	nA
On Char	acteristics (Note 2)			•	•	
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	2.6	4	V
$\Delta V_{GS(th)} \ \Delta T_J$	Gate Threshold Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		-7		mV/°C
R _{DS(on)}	Static Drain-Source	$V_{GS} = 10 \text{ V}, \qquad I_{D} = 11 \text{ A}$		61	80	mΩ
	On–Resistance	$V_{GS} = 6.0 \text{ V}, \qquad I_{D} = 10 \text{ A}$		63	90	
		$V_{GS} = 10 \text{ V}, I_D = 11 \text{ A}, T_J = 125^{\circ}\text{C}$		127	175	
I _{D(on)}	On–State Drain Current	$V_{GS} = 10 \text{ V}, \qquad V_{DS} = 10 \text{ V}$	25			Α
g FS	Forward Transconductance	$V_{DS} = 10 \text{ V}, \qquad I_{D} = 11 \text{ A}$		39		S
Dynamic	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 75 \text{ V}, \qquad V_{GS} = 0 \text{ V},$		1911		pF
Coss	Output Capacitance	f = 1.0 MHz		106		pF
C _{rss}	Reverse Transfer Capacitance			33		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 75 \text{ V}, \qquad I_{D} = 1 \text{ A},$		12	22	ns
t _r	Turn-On Rise Time	$V_{GS} = 10 \text{ V}, \qquad R_{GEN} = 6 \Omega$		5	10	ns
t _{d(off)}	Turn-Off Delay Time			33	53	ns
t _f	Turn–Off Fall Time			23	37	ns
Q _g	Total Gate Charge	$V_{DS} = 75 \text{ V}, \qquad I_{D} = 11 \text{ A},$		40	56	nC
Q_{gs}	Gate-Source Charge	$V_{GS} = 10 \text{ V}$		7		nC
Q_{gd}	Gate-Drain Charge			12		nC
	ource Diode Characteristics	and Maximum Ratings			1	
Is	Maximum Continuous Drain–Source	Diode Forward Current			22	Α
V _{SD}	Drain–Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 11 A (Note 2)		0.83	1.3	V

Notes

- 1. Calculated continuous current based on maximum allowable junction temperature.
- 2. Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0%

Typical Characteristics

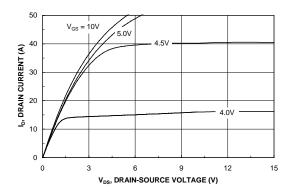


Figure 1. On-Region Characteristics.

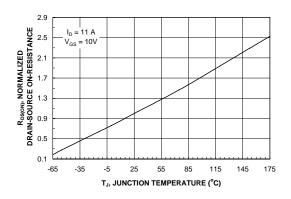


Figure 3. On-Resistance Variation with Temperature.

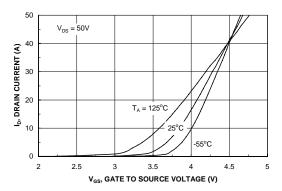


Figure 5. Transfer Characteristics.

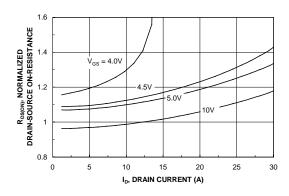


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

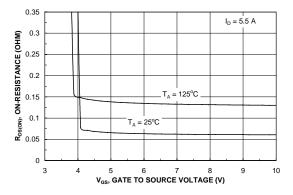


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

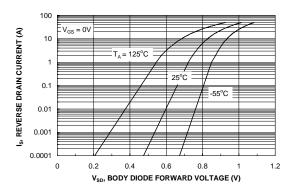
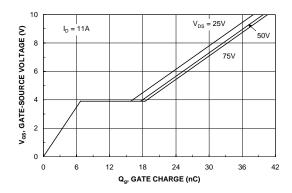


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



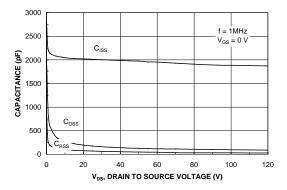


Figure 7. Gate Charge Characteristics.

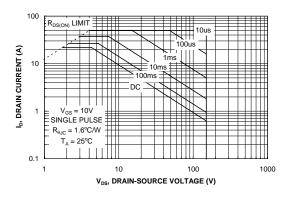


Figure 8. Capacitance Characteristics.

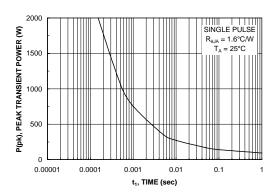


Figure 9. Maximum Safe Operating Area.

Figure 10. Single Pulse Maximum Power Dissipation.

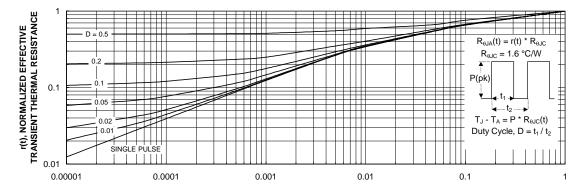


Figure 11. Transient Thermal Response Curve.

Thermal characterization performed using the conditions described in Note 1. Transient thermal response will change depending on the circuit board design.

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